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SHEET 1 OF 1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 214505US8PCT	SERIAL NO. 09/926,281		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT		Yuichi WATANABE			
		FILING DATE October 23, 2001		GROUP 2838			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AB	AA	6,150,798	11/21/2000	C. FERRY, et al.	—	—	
AB	AB	6,011,416	01/04/2000	F. MIZUNO, et al.	—	—	
AB	AC						
AB	AD						
AB	AE						
AB	AF						
AB	AG						
AB	AH						
AB	AI						
AB	AJ						
AB	AK						
AB	AL						
AB	AM						
AB	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
AB	AO	11-297713	10/29/99	JAPAN (submitting English translation only)			
AB	AP	7-303373	11/14/95	JAPAN (submitting English translation only)			
AB	AQ	11-164550	06/18/99	JAPAN (submitting corr. US 6,150,798 only)			
AB	AR	9-233810	09/05/97	JAPAN (submitting English translation only)			
AB	AS	860 946	08/26/98	EUROPE (submitting corr. US 6,011,416 and JP 10-41797 only)			
AB	AT	10-41797	02/13/98	JAPAN		X	
AB	AU						
AB	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AB	AW	J. C. ZOLPER, 1999 International Electron Devices Meeting, Technical Digest, pages 389-392, "WIDE BANDGAP SEMICONDUCTOR MICROWAVE TECHNOLOGIES: FROM PROMISE TO PRACTICE", 1999					
AB	AX	S. YOSHIDA, The Furukawa Electric Co., Ltd., vol. 68, no. 7, pages 787-792, "ELECTRONIC DEVICE USING GaN", 1999 (submitting English translation only, pages 1-20)					
	AY						
	AZ						
Examiner	<i>A. Berlanc</i>				Date Considered	<i>8/8/03</i>	
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

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